

High Performance Differential Probes

P7350 • P7330 • P6330

Features & Benefits

- <100 ps Risetime (P7350 Guaranteed)
- 5 GHz to 3.5 GHz Bandwidths (Typical)
- Low Input Capacitance:
- <0.3 pF Differential (P7350 Typical)
- ≥ 60 dB (1000:1) Common Mode Rejection Ratio (CMRR) at 1 MHz (P7330, **P6330** typical)
- Small Probe Head Allows Easy Probing of SMDs
- P7350, P7330 TekConnect[®] Interface (can be used with CSA/TDS8000 Series via 80A03 TekConnect Interface Adapter)
- **P6330** TEKPROBE II[®] BNC interface (connects to TEKPROBE II BNC interface on TDS series oscilloscopes. Use 1103 TEKPROBE[®] power supply to interface with other BNC instruments)

Applications

- Communications (Gigabit Ethernet, Fibre Channel, InfiniBand)
- Semiconductor Characterization & Validation (PCI-Express, Serial ATA, IEEE 1394, USB 2.0, RAMBUS, DDR)
- Disk Drive Design

Tektronix' proven expertise in probes brings you the highest fidelity in high-speed differential probing. The P7350, P7330, **P6330** high BW differential probes offer excellent signal fidelity, meeting the needs of engineers in design & debug of technologies with very fast clock speeds and edge rates. They provide high-bandwidth, low circuit loading, low noise differential probing solutions for high-speed circuit designers.

P7350

The P7350 improves usability with variable spacing and solder down capability, and a small form factor for ease of use on densely packed circuit boards with difficult-to-reach probe points. It employs the patented TekConnect[®] Interface, which preserves signal integrity

to 10 GHz and beyond to meet present and future bandwidth needs.

P7330 and P6330

The P7330 and **P6330** enable users to make time domain or frequency domain measurements on high bandwidth signals commonly found in digital IC designs, communication applications, and disk drive applications. The P7330 and **P6330** provide high-bandwidth, low circuit loading, and low noise differential probing solutions. The small probe head geometry and assorted probe tip accessories allow these probes to easily accommodate manual probing of surface mount devices.